

SPECIFICATION

- ØSpectral range : 380~1040nm
- ØRepeatability :
Reflectivity : $\pm 1\%$ For SiO₂ 1000Å / Si , 30 times (1 σ) at 632.8 nm

CAPABILITY

Measurement Parameters

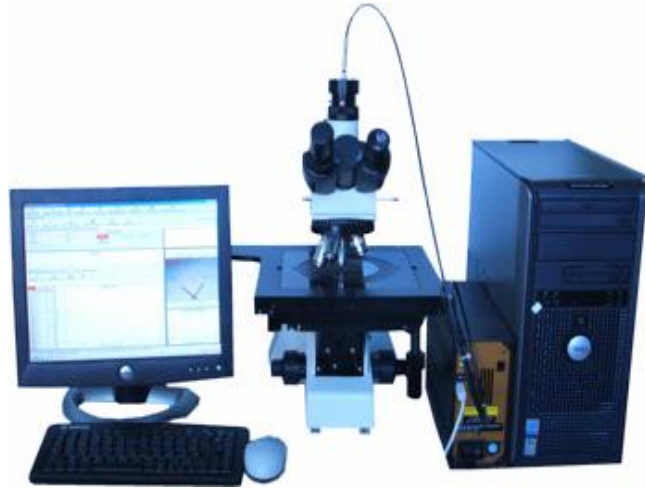
- ØTransmission (T%)
- ØReflection (R%)
- ØRefractive Index (n,k)
- ØThickness

Anisotropic Material Measurement

Unknown Film Measurement

- Ø50 μm > Tks > 2 μm
- Fast Fourier Transform
- ØTks < 5000 Å
- Auto Searching

FEATURES



Normal Incident Angle

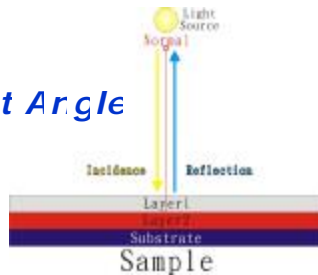
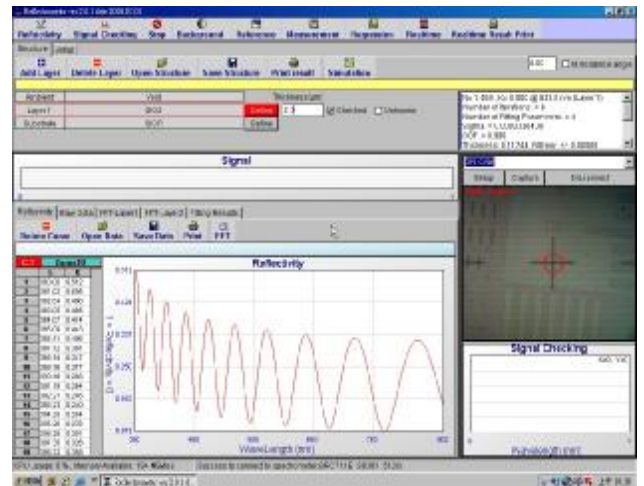
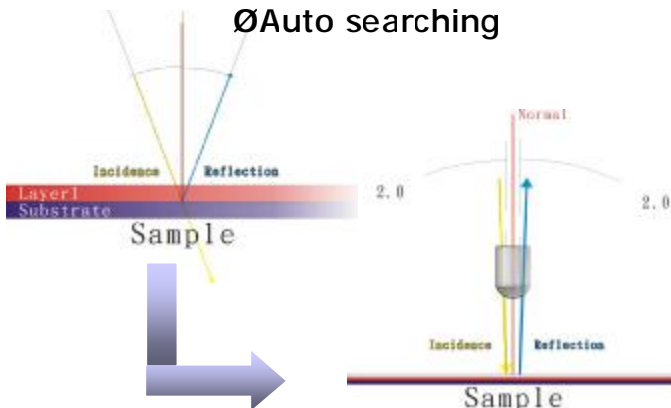


Image Digital CAM

- ØWhat you see = what you measure
- ØSmall spot: 40-80 μm

Curve Fitting

- ØFast Fourier Transform
- ØAuto searching



Automated incidence angle calibration

Fertiful Database

Compatible (N, K) files with SE